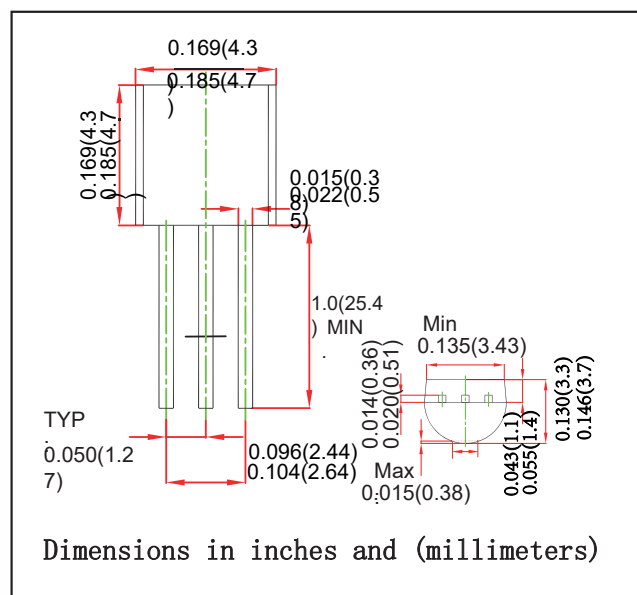


TO-92 PLASTIC SILICON RECTIFIERS
FEATURES

- Blocking voltage to 600 V
- RMS on-state current to 0.6 A
- Sensitive gate in all four quadrants
- Low cost package
- General purpose bidirectional switching

MECHANICAL DATA

- Case style:TO-92 molded plastic
- Mounting position:any


MAXIMUM RATINGS AND CHARACTERISTICS

@ 25°C Ambient Temperature (unless otherwise noted)

Parameter	Symbol	Conditions		Value	Unit
repetitive peak off-state voltage	V _{DRM}	T _j =25 to125°C		600	V
on-state current (RMS value)	I _{T(RMS)}	full sine wave; T _{lead} ≤51 °C		0.8	A
non-repetitive peak on-state current	I _{TSM}	full sine wave; T _j =25°C prior to surge	t=20ms	8.0	A
			t = 16.7ms	8.8	A
I ² t for fusing	I ² t	t=10 ms		1.28	A ² s
repetitive rate of rise of on-state current after triggering	di _T /dt	I _{TM} = 1.0 A; I _G = 0.2 A; di _G /dt = 0.2 A/μs	T2+ G+	50	A/μs
			T2+ G-	50	
			T2- G-	50	
			T2- G+	10	
gate current (peak value)	I _{GM}	t = 2μs max		2	A
gate voltage (peak value)	V _{GM}	t = 2μs max		5	V
gate power (peak value)	P _{GM}	t = 2μs max		5	W
average gate power	P _{G(AV)}	T _{case} =80°C; t = 2μs max		0.5	W
storage temperature	T _{stg}			-40~ +150	C
operating junction temperature	T _j			-40~ +110	C
thermal resistance from junction to lead	R _{th(j-lead)}	full cycle		60	K/W
		half cycle		80	K/W
thermal resistance from junction to ambient	R _{th(j-a)}	mounted on a printed circuit board; lead length = 4 mm		150	K/W

TO-92 Plastic-Encapsulate Transistors

Parameter	Symbol	Test conditions		Min	Max	Unit
Static characteristics						
gate trigger current	I _{GT}	V _D = 12V; I _T = 0.1A	T2+ G+		3	mA
			T2+ G-		3	
			T2- G-		3	
			T2- G+		7	
latching current	I _L	V _D = 12V; I _{GT} = 0.1A	T2+ G+		5	mA
			T2+ G-		8	
			T2- G-		5	
			T2- G+		8	
holding current	I _H	V _D = 12 V; I _{GT} = 0.1 A			5	mA
on-state voltage	V _{TM}	I _T = 1.0 A			1.65	V
gate trigger voltage	V _{GT}	V _D = 12 V; I _T = 0.1 A			1.5	V
		V _D =400V; I _T = 0.1 A; T _j = 110°C		0.2		
off-state leakage current	I _D	V _D =V _{DRM (max)} ; T _j = 125°C			0.5	mA

Dynamic characteristics

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
critical rate of rise of off-state voltage	dV_D/dt	$V_D = 67\% \text{ of } V_{DM(max)};$ $T_{case} = 110^\circ C;$ exponential waveform; gate open circuit	5	15		V/ μs
critical rate of rise of commutation voltage	dV_{com}/dt	$V_D = \text{rated } V_{DRM}; T_{case} = 50^\circ C$ $I_{TM} = 0.84A$ Commutating $di/dt = 0.3A/ms$		5		V/ μs
gate controlled turn-on time	t_{gt}	$I_{TM} = 1.5A; V_D = V_{DRM(max)}$ $I_G = 100mA; di_G/dt = 5A/\mu s$		2		μs

RATINGS AND CHARACTERISTIC CURVES

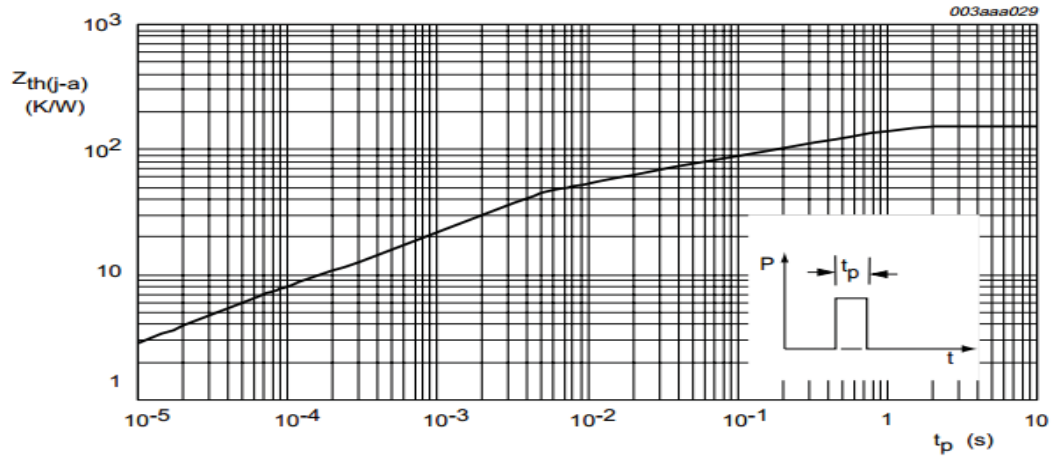
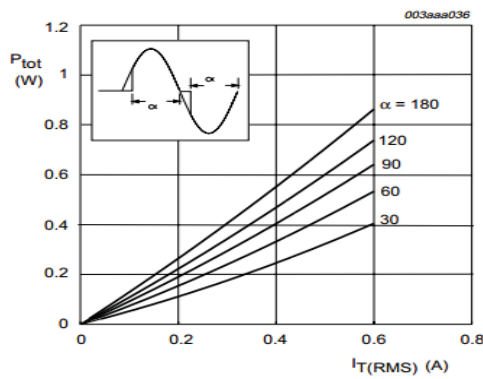
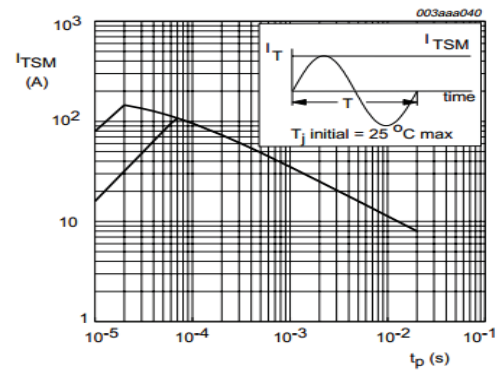


Fig 1. Transient thermal impedance from junction to ambient as a function of pulse duration.



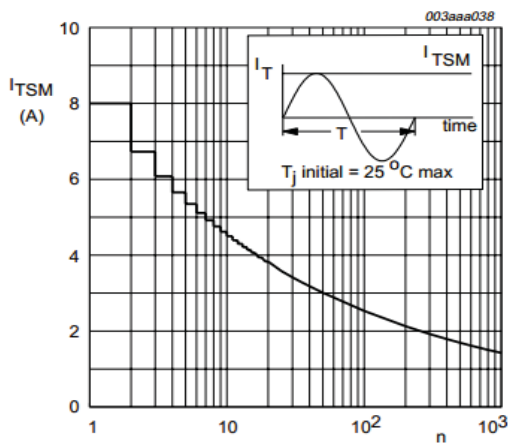
α = conduction angle

Fig 2. Maximum on-state dissipation as a function of RMS on-state current; typical values.



$t_p \leq 20$ ms

Fig 3. Maximum permissible non-repetitive peak on-state current as a function of pulse width for sinusoidal currents; typical values.



n = number of cycles at $f = 50$ Hz

Fig 4. Maximum permissible non-repetitive peak on-state current as a function of number of cycles for sinusoidal currents; typical values.

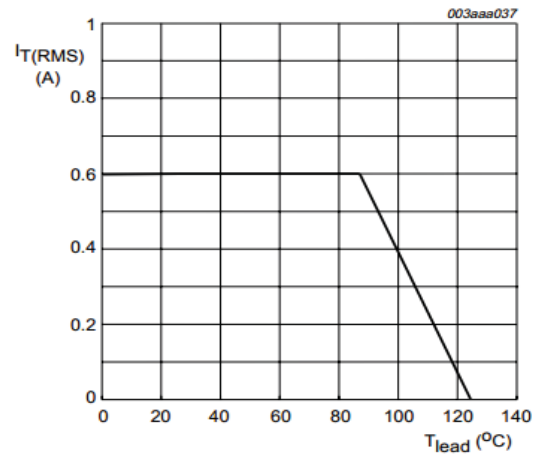
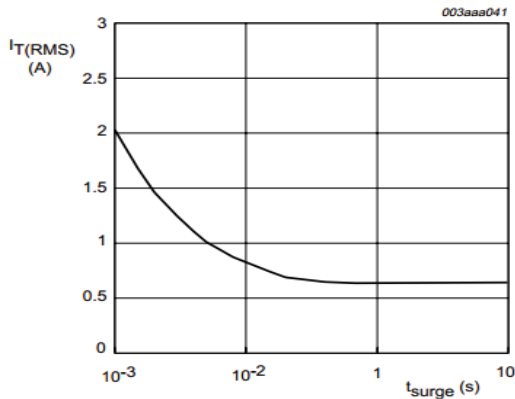


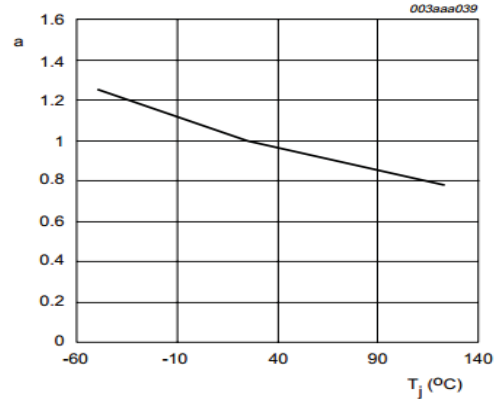
Fig 5. Maximum permissible RMS current as a function of lead temperature; typical values.

RATINGS AND CHARACTERISTIC CURVES



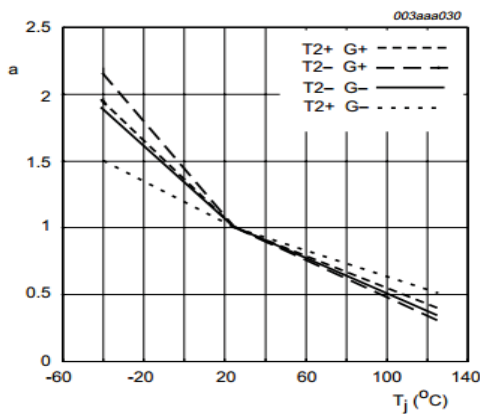
$f = 50 \text{ Hz}$; $T_{lead} \leq 50^\circ \text{C}$

Fig 6. Maximum permissible repetitive RMS on-state current as a function of surge duration for sinusoidal currents; typical values.



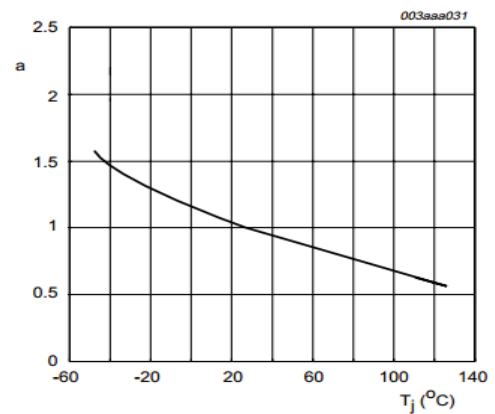
$$a = \frac{V_{GT(T_j)}}{V_{GT(25^\circ\text{C})}}$$

Fig 7. Normalized gate trigger voltage as a function of junction temperature; typical values.



$$a = \frac{I_{GT(T_j)}}{I_{GT(25^\circ\text{C})}}$$

Fig 8. Normalized gate trigger current as a function of junction temperature; typical values.



$$a = \frac{I_{L(T_j)}}{I_{L(25^\circ\text{C})}}$$

Fig 9. Normalized latching current as a function of junction temperature; typical values.

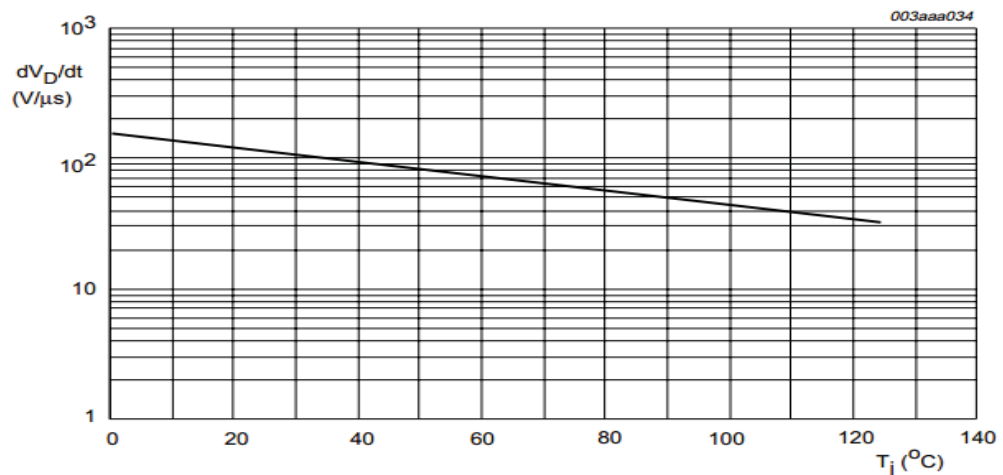


Fig 12. Critical rate of rise of off-state voltage as a function of junction temperature; typical values.